

**Search Notes**

Application/Control No.

10/626,693

Examiner

Madeleine AV Nguyen

Applicant(s)/Patent under  
Reexamination

MEYER, JOHN F.

Art Unit

2625

**SEARCHED**

Class	Subclass	Date	Examiner
358	1.9	10/11/2006	AV
	1.15		
	400		
	442		
	444		
	468		
379	100.01		
358	500		
	1.15		
358	1.16		
	1.13		
358	1.1		
348	207.1		
348	207.2	10/11/2006	AV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	10/11/2006	AV
East	10/12/2006	AV